

N-Channel Enhancement Mode MOSFET

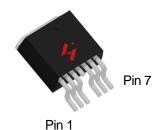
Feature

- 100V/322A $R_{DS(ON)=1.4m}\Omega(typ.)@V_{GS}=10V$
- 100% Avalanche Tested
- Reliable and Rugged
- Halogen-Free and Green Devices Available (RoHS Compliant)

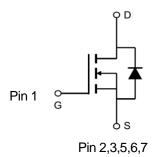
Applications

- Energy Storage
- Battery Protection
- Battery Operated Tools

Pin Description



TO-263-6L



Single N-Channel MOSFET

Ordering and Marking Information



Note: HUAYI lead-free products contain molding compounds/die attach materials and 100% matte tin plateTermi-Nation finish; which are fully compliant with RoHS. HUAYI lead-free products meet or exceed the lead-Free requirements of IPC/JEDEC J-STD-020 for MSL classification at lead-free peak reflow temperature. HUAYI defines "Green" to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

HUAYI reserves the right to make changes, corrections, enhancements, modifications, and improvements to this pr-oduct and/or to this document at any time without notice.



Absolute Maximum Ratings

Symbol	Parameter	Rating	Unit	
Common Rat	tings (Tc=25°C Unless Otherwise Noted)			
VDSS	Drain-Source Voltage		100	V
Vgss	Gate-Source Voltage		±20	V
TJ	Junction Temperature Range		-55 to 175	°C
Tstg	Storage Temperature Range		-55 to 175	°C
ls	Source Current-Continuous(Body Diode) Tc=25°C		322	А
Mounted on	Large Heat Sink			•
Ірм	Pulsed Drain Current *	Tc=25°C	1288	А
	Continuous Drain Compant	Tc=25°C	322	А
ID	Io Continuous Drain Current	Tc=100°C	228	А
		Tc=25°C	375	W
Po	Maximum Power Dissipation	Tc=100°C	187.5	W
R _θ /c	Thermal Resistance, Junction-to-Case		0.4	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient **		40	°C/W
Eas	Single Pulsed-Avalanche Energy ***	L=0.3mH	1102	mJ

Note: *

Electrical Characteristics (Tc = 25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	HYG018N10NS1		l loit		
Symbol	Farameter	rest Conditions	Min	Тур.	Max	Unit	
Static Char	Static Characteristics						
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V,I _{DS} =250μA	100	-	-	V	
lpss	VDS=100V,VGS=0V		-	-	1.0	μA	
IDSS	Drain-to-Source Leakage Current	TJ=125°C	-	-	50	μA	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250µA	2	3	4	V	
Igss	Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	±100	nA	
RDS(ON)*	Drain-Source On-State Resistance	V _{GS} =10V,I _{DS} =100A	-	1.4	1.7	mΩ	
Diode Char	Diode Characteristics						
VsD*	Diode Forward Voltage	IsD=100A,Vgs=0V	-	0.86	1.2	V	
trr	Reverse Recovery Time	Isp=100A,dIsp/dt=100A/µs	-	105	-	ns	
Qrr	Reverse Recovery Charge	15D=100A,α15D/α(=100A/μS	-	208	-	nC	

^{*} Repetitive rating; pulse width limited by max. junction temperature.

^{**} Surface mounted on FR-4 board.

^{***} Limited by TJmax, starting TJ=25°C, L = 0.3mH, VDS=80V, VGS =10V.

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Electrical Characteristics (Cont.) (Tc =25°C Unless Otherwise Noted)

Cumple of	Davamatar	Test Conditions	HY	HYG018N10NS1		
Symbol	Parameter	lest Conditions	Min	Тур.	Max	Unit
Dynamic (Dynamic Characteristics					
Rg	Gate Resistance	V _{GS} =0V,V _{DS} =0V,F=1MHz	-	1.1	-	Ω
Ciss	Input Capacitance	Vgs=0V,	-	12570	-	
Coss	Output Capacitance	V _{DS} =25V,	-	5450	-	pF
Crss	Reverse Transfer Capacitance	Frequency=1MHz	-	208	-	
td(ON)	Turn-on Delay Time		-	43	-	
Tr	Turn-on Rise Time	$V_{DD}=50V,R_{G}=4\Omega,$	-	109	-	
td(OFF)	Turn-off Delay Time	Ips=100A,Vgs=10V	-	100	-	ns
Tf	Turn-off Fall Time		-	125	-	
Gate Charge Characteristics						
Qg	Total Gate Charge		-	190	-	
Qgs	Gate-Source Charge	V _{DS} =80V, V _{GS} =10V, I _D =100A	-	65	-	nC
Qgd	Gate-Drain Charge		-	42	-	

Note: *Pulse test, pulse width \leq 300us, duty cycle \leq 2% (10V)



Typical Operating Characteristics

Figure 1: Power Dissipation

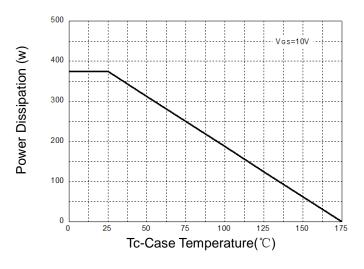


Figure 2: Drain Current

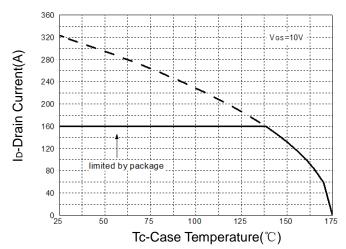


Figure 3: Safe Operation Area

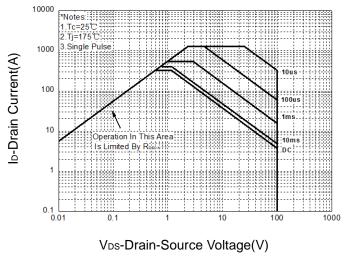
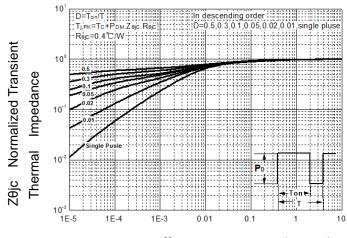


Figure 4: Thermal Transient Impedance



Maximum Effective Transient Thermal Impedance, Junction-to-Case

Figure 5: Output Characteristics

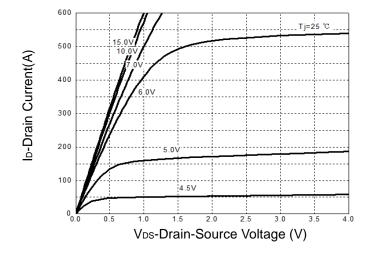
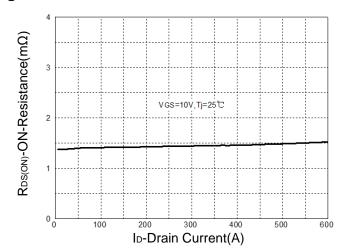


Figure 6: Drain-Source On Resistance





Typical Operating Characteristics(Cont.)

Figure 7: On-Resistance vs. Temperature

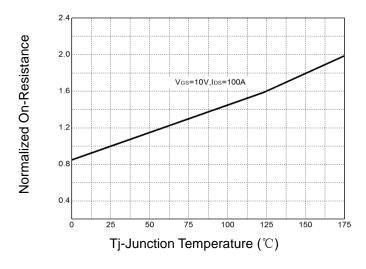


Figure 8: Source-Drain Diode Forward

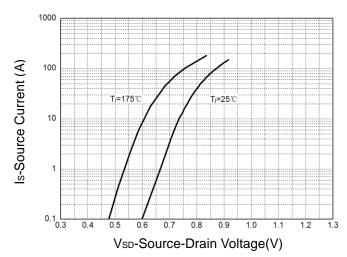


Figure 9: Capacitance Characteristics

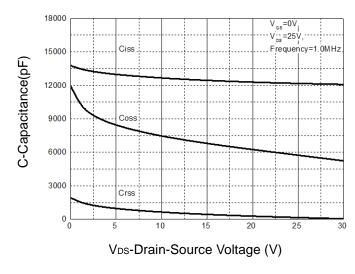
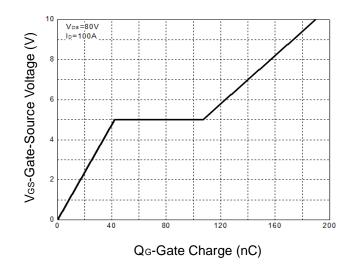
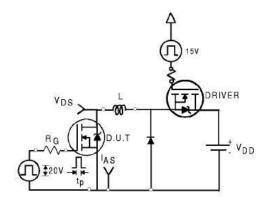


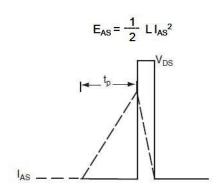
Figure 10: Gate Charge Characteristics



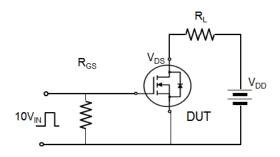


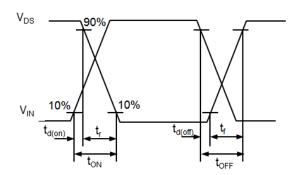
Avalanche Test Circuit



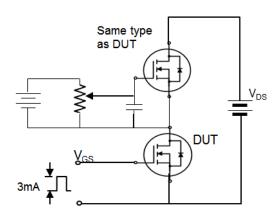


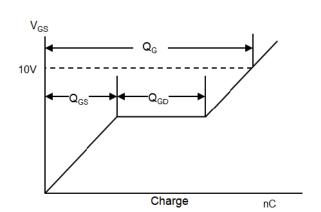
Switching Time Test Circuit





Gate Charge Test Circuit





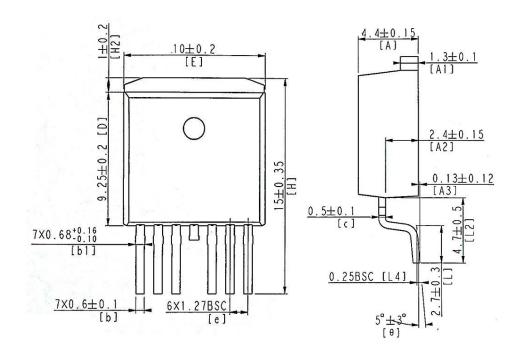


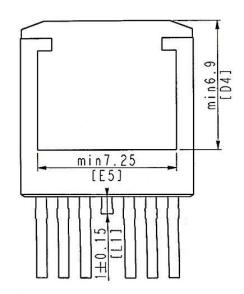
Device Per Unit

Package Type	Unit	Quantity
TO-263-6L	Reel	800

Package Information

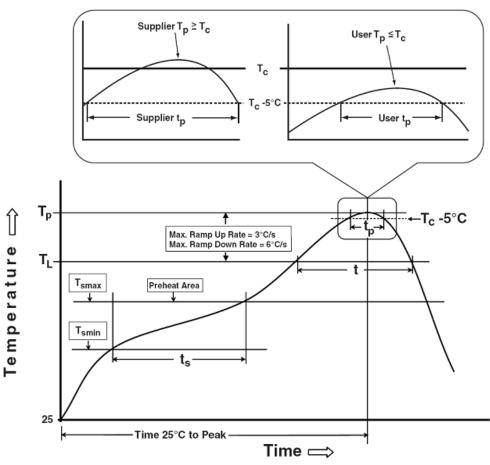
TO-263-6L







Classification Profile



Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
Preheat & Soak Temperature min (T _{smin}) Temperature max (T _{smax}) Time (Tsmin to Tsmax) (t _s)	100 °C 150 °C 60-120 seconds	150 °C 200 °C 60-120 seconds
Average ramp-up rate (T _{smax} to T _P)	3 °C/second max.	3°C/second max.
Liquidous temperature (T _L) Time at liquidous (t _L)	183 °C 60-150 seconds	217 °C 60-150 seconds
Peak package body Temperature (Tp)*	See Classification Temp in table 1	SeeClassification Tempin table 2
Time (t _P)** within 5°C of the specified classification temperature (T _c)	20** seconds	30** seconds
Average ramp-down rate (Tpto Tsmax)	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.

^{*}Tolerance for peak profile Temperature (Tp) is defined as a supplier minimum and a user maximum.

^{**} Tolerance for time at peak profile temperature (tp) is defined as a supplier minimum and a user maximum.

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Table 1.SnPb Eutectic Process – Classification Temperatures (Tc)

Package Thickness	Volume mm³ <350	Volume mm³ ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2.Pb-free Process – Classification Temperatures (Tc)

Package	Volume mm ³	Volume mm³	Volume mm³
Thickness	<350	350-2000	≥2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
PRECON	JESD-22, A113	30°C/60%/192Hrs
HTRB	JESD-22, A108	168/500/1000 Hrs, Bias @ 150°C
HTGB	JESD-22, A108	168 /500/1000Hrs, Vgs100% @ 150°C
PCT	JESD-22, A102	96 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -55°C~150°C

Customer Service

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